

FORM PTO-1449 INFORMATION DISCLOSURE CITATIONS IN AN APPLICATION	Atty Docket:	58551.US	Serial #:
	Applicant:	Patrick Y. Huet et al.	
	Filing Date:	2003.11.19	Group:

#### U.S. PATENT DOCUMENTS

Examiner Initial	Cite #	Document Number	Date	Name	Class	Sub-Class	Filing Date
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#### FOREIGN PATENT DOCUMENTS

Examiner Initial	Cite #	Document Number	Date	Country	Class	Sub-Class	Translation
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#### OTHER NON-PATENT DOCUMENTS

Examiner Initial	Cite #	Author, title, date, pertinent pages, etc.
RAR	1	Diebold et al., <i>Handbook of Silicon Semiconductor Metrology</i> , SEMATECH publication, year unknown, pgs 25-30 and relevant figures.

Examiner	/Richard Rosenberger/	Date Considered:	02/28/2007
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.			